



<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10668010</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>SINHA ET AL.</p>
	<p>Examiner</p> <p>Kaplan, Hal I</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
307	651	07/14/2006	HK
374	172	07/14/2006	HK
374	176	07/14/2006	HK
702	99	07/14/2006	HK
U.S. Patent and Trademark Office		Part of Paper No.:	20060716

<b>Search Notes</b>  	Application/Control No.  10668010	Applicant(s)/Patent Under Reexamination  SINHA ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Notes	Date	Examiner
374/1,170,172,176,178 (consulted Gail Verbitsky)	02/14/2006	HK
702/99,130 (consulted Bryan Bui)	02/15/2006	HK
EAST (US-PGPUB,USPAT,USOCR,EPO,JPO,DERWENT,IBM_TDB) - See Search History Printout	07/14/2006	HK
U.S. Patent and Trademark Office		Part of Paper No.: 20060716